

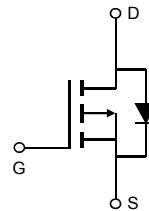
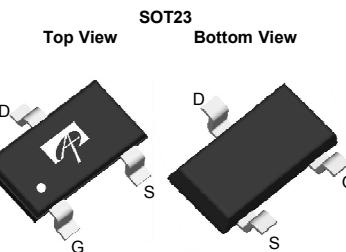
### General Description

The AO3481 uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation gate voltages as low as 2.5V. This device is suitable for use as a load switch or other general applications.

- RoHS and Halogen-Free Compliant

### Product Summary

$V_{DS}$	-30V
$I_D$ (at $V_{GS}=-10V$ )	-4.0A
$R_{DS(ON)}$ (at $V_{GS}=-10V$ )	< 50mΩ
$R_{DS(ON)}$ (at $V_{GS}=-4.5V$ )	< 60mΩ
$R_{DS(ON)}$ (at $V_{GS}=-2.5V$ )	< 85mΩ



### Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	$V_{DS}$	-30	V
Gate-Source Voltage	$V_{GS}$	$\pm 12$	V
Continuous Drain Current Current	$I_D$	-4	A
		-3.2	
Pulsed Drain Current <sup>C</sup>	$I_{DM}$	-27	
Power Dissipation <sup>B</sup>	$P_D$	1.4	W
		0.9	
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	°C

### Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup> $t \leq 10s$	$R_{\theta JA}$	70	90	°C/W
Maximum Junction-to-Ambient <sup>A,D</sup> Steady-State		100	125	°C/W
Maximum Junction-to-Lead	$R_{\theta JL}$	63	80	°C/W

**Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$I_D=-250\mu\text{A}, V_{GS}=0\text{V}$	-30			V
$I_{\text{DSS}}$	Zero Gate Voltage Drain Current	$V_{DS}=-30\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$			-1 -5	$\mu\text{A}$
$I_{\text{GSS}}$	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}= \pm 12\text{V}$			$\pm 100$	nA
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=-250\mu\text{A}$	-0.5	-0.9	-1.3	V
$I_{\text{D(ON)}}$	On state drain current	$V_{GS}=-10\text{V}, V_{DS}=-5\text{V}$	-27			A
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$V_{GS}=-10\text{V}, I_D=-4.0\text{A}$ $T_J=125^\circ\text{C}$		41 62	50 75	$\text{m}\Omega$
		$V_{GS}=-4.5\text{V}, I_D=-3.5\text{A}$		47	60	$\text{m}\Omega$
		$V_{GS}=-2.5\text{V}, I_D=-2.5\text{A}$		60	85	$\text{m}\Omega$
$g_{\text{FS}}$	Forward Transconductance	$V_{DS}=-5\text{V}, I_D=-4.0\text{A}$		17		S
$V_{\text{SD}}$	Diode Forward Voltage	$I_S=-1\text{A}, V_{GS}=0\text{V}$		-0.7	-1	V
$I_S$	Maximum Body-Diode Continuous Current				-2	A
<b>DYNAMIC PARAMETERS</b>						
$C_{\text{iss}}$	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=-15\text{V}, f=1\text{MHz}$		645		$\text{pF}$
$C_{\text{oss}}$	Output Capacitance			80		$\text{pF}$
$C_{\text{rss}}$	Reverse Transfer Capacitance			55		$\text{pF}$
$R_g$	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$	4	7.8	12	$\Omega$
<b>SWITCHING PARAMETERS</b>						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=-10\text{V}, V_{DS}=-15\text{V}, I_D=-4.0\text{A}$		14	20	$\text{nC}$
$Q_g(4.5\text{V})$	Total Gate Charge			7		$\text{nC}$
$Q_{\text{gs}}$	Gate Source Charge			1.5		$\text{nC}$
$Q_{\text{gd}}$	Gate Drain Charge			2.5		$\text{nC}$
$t_{\text{D(on)}}$	Turn-On Delay Time	$V_{GS}=-10\text{V}, V_{DS}=-15\text{V}, R_L=3.75\Omega, R_{\text{GEN}}=3\Omega$		6.5		ns
$t_r$	Turn-On Rise Time			3.5		ns
$t_{\text{D(off)}}$	Turn-Off Delay Time			41		ns
$t_f$	Turn-Off Fall Time			9		ns
$t_{\text{rr}}$	Body Diode Reverse Recovery Time		$I_F=-4.0\text{A}, dI/dt=100\text{A}/\mu\text{s}$	11		ns
$Q_{\text{rr}}$	Body Diode Reverse Recovery Charge	$I_F=-4.0\text{A}, dI/dt=100\text{A}/\mu\text{s}$		3.5		$\text{nC}$

A. The value of  $R_{\text{QJA}}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A = 25^\circ\text{ C}$ . The value in any given application depends on the user's specific board design.

B. The power dissipation  $P_D$  is based on  $T_{J(\text{MAX})}=150^\circ\text{ C}$ , using  $\leq 10\text{s}$  junction-to-ambient thermal resistance.

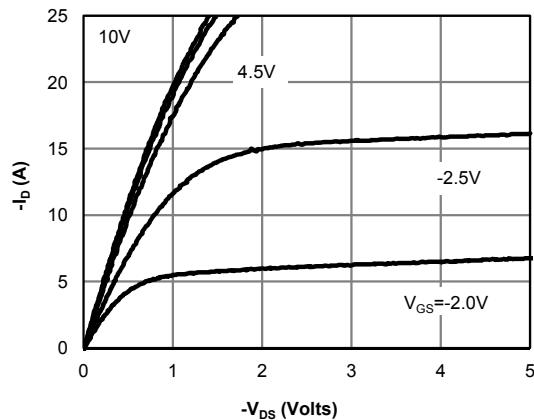
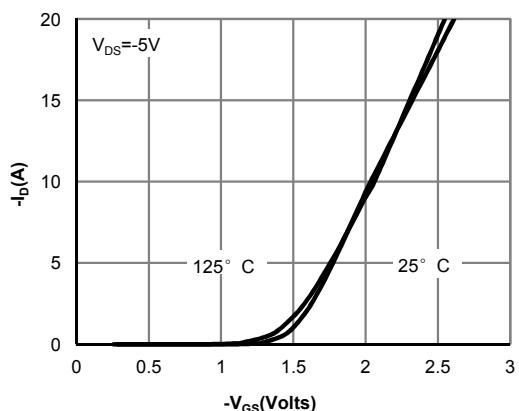
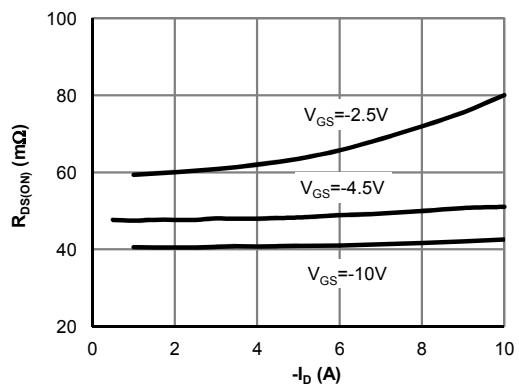
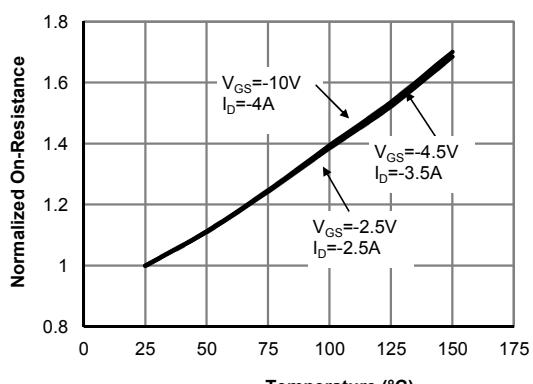
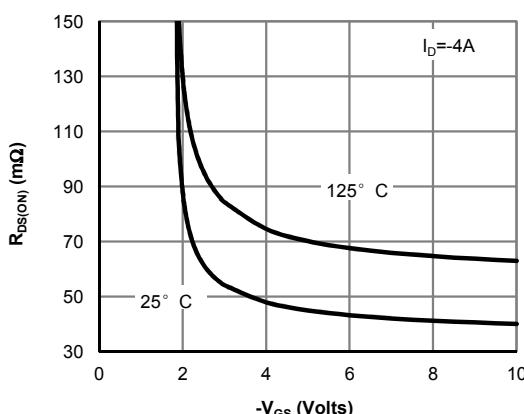
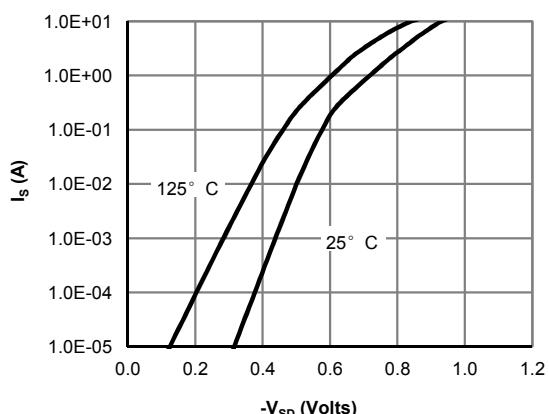
C. Repetitive rating, pulse width limited by junction temperature  $T_{J(\text{MAX})}=150^\circ\text{ C}$ . Ratings are based on low frequency and duty cycles to keep initial  $T_J=25^\circ\text{ C}$ .

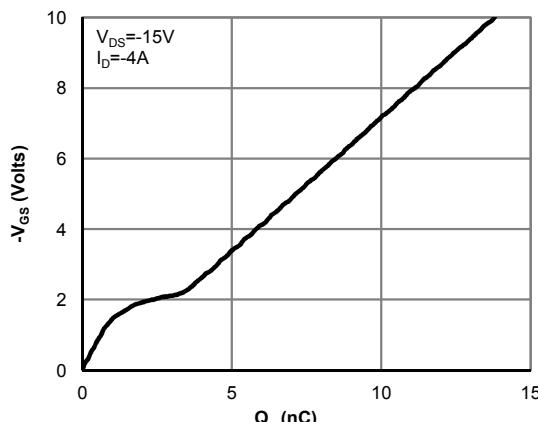
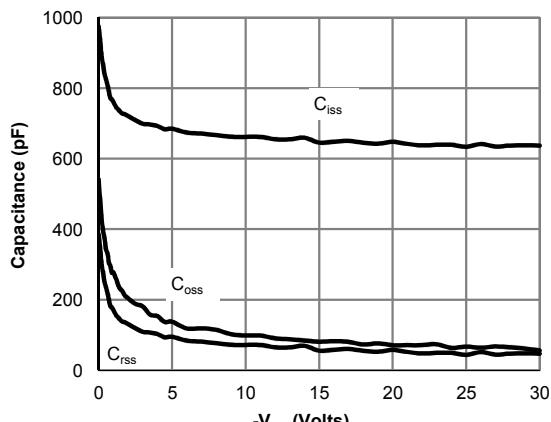
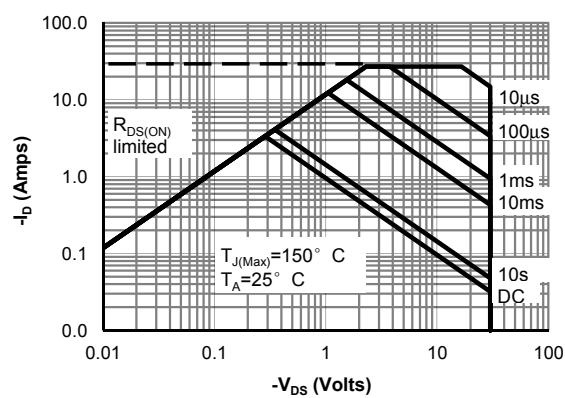
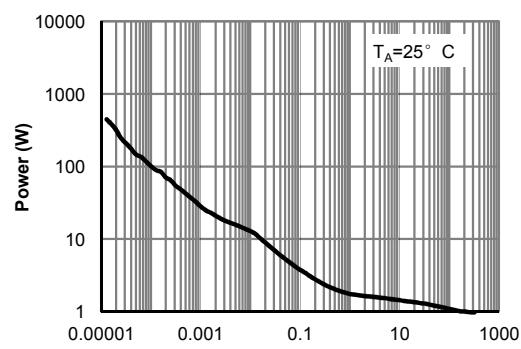
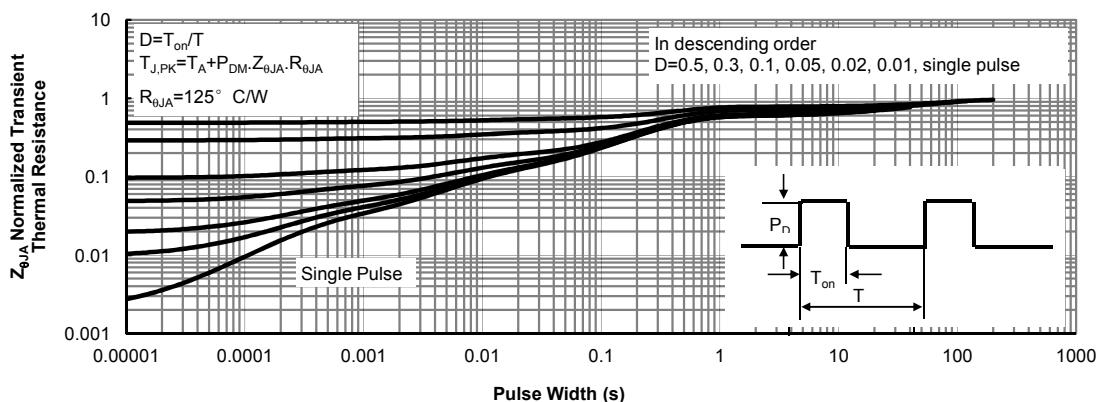
D. The  $R_{\text{QJA}}$  is the sum of the thermal impedance from junction to lead  $R_{\text{QJL}}$  and lead to ambient.

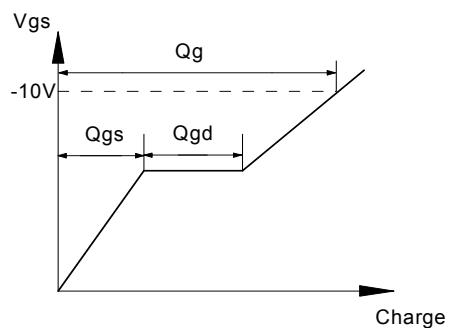
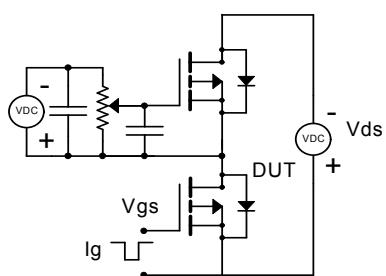
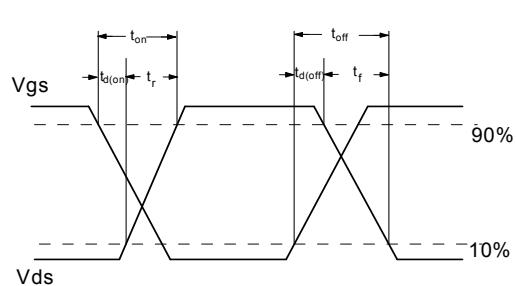
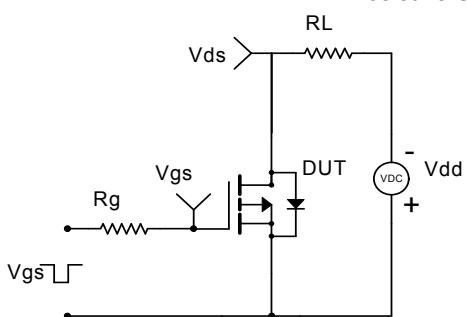
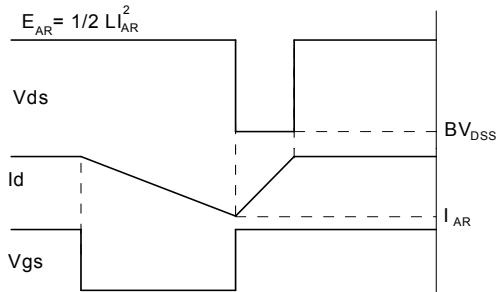
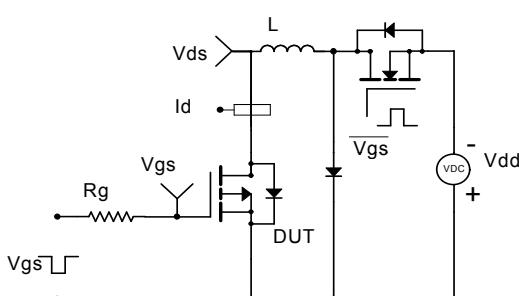
E. The static characteristics in Figures 1 to 6 are obtained using  $<300\mu\text{s}$  pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-ambient thermal impedance which is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, assuming a maximum junction temperature of  $T_{J(\text{MAX})}=150^\circ\text{ C}$ . The SOA curve provides a single pulse rating.

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**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

**Fig 1: On-Region Characteristics (Note E)**

**Figure 2: Transfer Characteristics (Note E)**

**Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)**

**Figure 4: On-Resistance vs. Junction Temperature (Note E)**

**Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)**

**Figure 6: Body-Diode Characteristics (Note E)**

**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

**Figure 7: Gate-Charge Characteristics**

**Figure 8: Capacitance Characteristics**

**Figure 9: Maximum Forward Biased Safe Operating Area (Note F)**

**Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note F)**

**Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)**

**Gate Charge Test Circuit & Waveform**

**Resistive Switching Test Circuit & Waveforms**

**Unclamped Inductive Switching (UIS) Test Circuit & Waveforms**

**Diode Recovery Test Circuit & Waveforms**
